2025 INTERNATIONAL TEST CONFERENCE

September 21 - 26, 2025
SAN DIEGO, CA, USA

Call for IEEE Formal Posters

The International Test Conference (ITC) is the world's premier venue dedicated to the electronic test of devices, boards and systems—covering the complete cycle from design verification, design- for-test, design-for-manufacturing, silicon debug, manufacturing test, system test, diagnosis, reliability and failure analysis, and back to process and design improvement.

Authors are invited to submit original, unpublished papers describing recent work in the field of testing and testable design. Of particular interest are works dedicated to the topics listed on the right and/or works focused on special tracks such as **Automotive Reliability, Reliability of AI HW and usage of AI for Testing, 3D/2.5D and Chiplet Testing, or HW Security**. Authors are also invited to submit practical, industry-oriented papers.

Submissions must include:

- Title of paper.
- Name, affiliation, e-mail address of each author. (Double blind review is not required).
- The corresponding author(s). ITC will communicate with the corresponding author(s).
- An electronic copy of a complete paper of **4 pages**.
- An abstract of 110 words or less to be entered online.

Posters are a useful way of presenting late-breaking results, getting feedback on an innovative method, or participating without having to write a full paper. Acceptance as a poster does not preclude submission of a more complete work as an ITC paper in 2026. Additional information on poster submissions will be provided on the ITC web page.

Poster submission deadline:	**May 20, 2025**
Author notification:	**June 15, 2025**

Accepted contributions after a peer review process will be indexed in **IEEE Xplore**. The presenters of the accepted IEEE FORMAL Posters are invited to give a pitch on stage and have to prepare a poster to illustrate during poster sessions at ITC25.

Test Week tutorial and workshop proposals are also welcomed. Deadlines and other information about proposals can be obtained from TTTC at: http://tab.computer.org/tttc

For detailed information about the submission process, requirements and deadlines, the selection process, and any other questions regarding the program itself or contact information, please consult the ITC web site at http://www.itctestweek.org.

For further information:

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ITC invites submissions on the latest advances in test, validation, diagnosis and security of IPs, ICs, boards and systems.

Topics of interest include, but not limited to:

3D/2.5D Test
5G/6G Test
Adaptive Test in Practice
AI/Machine Learning in Test
ATE/Probe Card Design
Automotive Reliability
Advances in Boundary Scan
Built-In Self-Test
Data Driven Test Methods
Defect-oriented Testing
Design for Test (DFT)
DFM and Test
Diagnosis
Economics of Test
End-to-End Data Analysis
End-to-End System Security
Emerging Defect Mechanisms
Field Monitoring, Test, & Debug
Hardware Security and Trust
IoT Testing
Jitter, High-Speed I/O and RF Test
Known-Good-Die Test
Memory Test and Repair
MEMS Testing
Mixed-Signal and Analog Test
New Technologies and Test
Online Test
Pre-Silicon/Post-Silicon Verification
Power Issues in Test
Protocol-aware Test
Quantum Device Testing
Reliability and Resilience
SoC/SiP/NoC Test
Silent Data Corruption
Silicon Debug
Simulation and Emulation
System Test (Applications)
System Test (Hardware/Software)
Test Compression
Test-to-Design Feedback
Test Escape Analysis
Test Flow Optimizations
Test Generation and Validation
Test Resource Partitioning
Test Standards
Testing High Speed Optics/Photonics
Timing Test
Yield Analysis and Optimization